

Notice of References Cited	Application/Control No. 10/724,641		Applicant(s)/Patent Under Reexamination DIERICKX ET AL.	
	Examiner Deborah Yee		Art Unit 1742	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,558,483	05-2003	Nakamura et al.	148/332
*	B	US-RE28,523	08-1975	Hill et al.	420/8
	C	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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